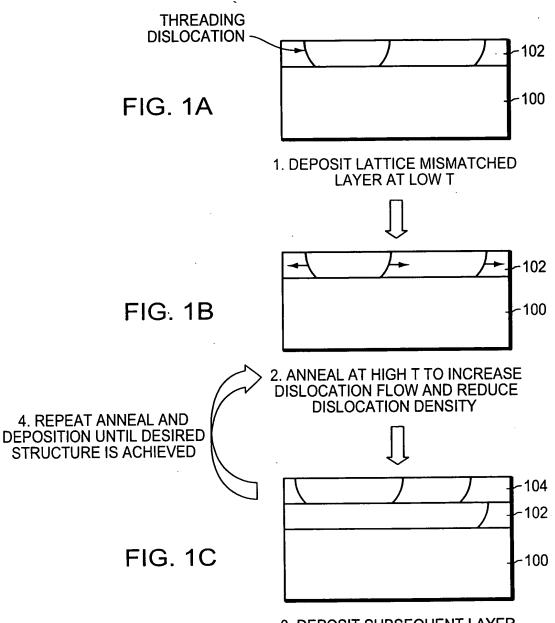


Title: Low Threading Dislocation Density Relaxed Mismatched Epilayers without High Temperature Growth Inventor: Fitzgerald Serial No. 09/761,497

EXPRESS MAIL LABEL NO. EV173088315US Attorney for Applicant: Mark L. Beloborodov



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3. DEPOSIT SUBSEQUENT LAYER
WITH INCREASED LATTICE
MISMATCHED AT LOW T





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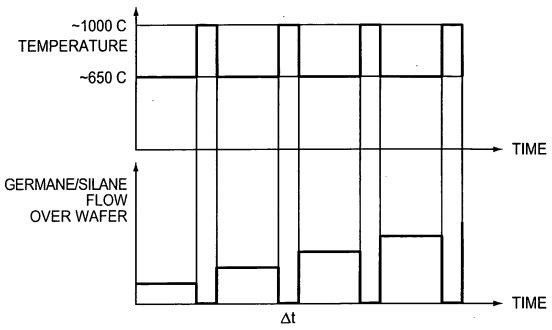
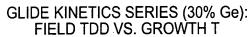


FIG. 2



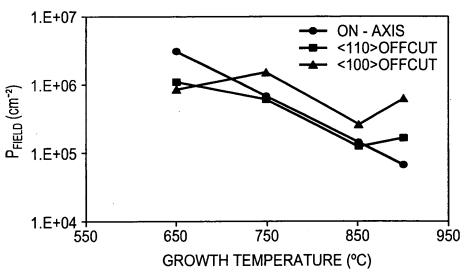


FIG. 3



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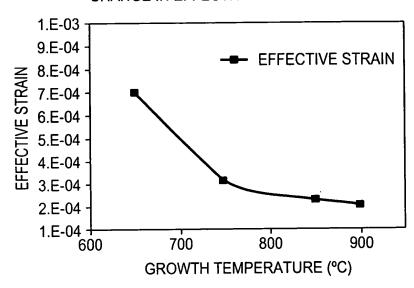


FIG. 4

SAMPLE	TOTAL THREADING DISLOCATION DENSITY (# / cm²)	FIELD THREADING DISLOCATION DENSITY (# / cm²)
20% SiGe ON Si WITH GRADED BUFFER AS GROWN	1.36 x 10 ⁶	1.31 x 10 ⁶
20% SiGe ON Si WITH GRADED BUFFER AFTER A 5 MIN ANNEAL AT 1050 °C	7.25 x 10 ⁵	5.48 x 10 ⁵

FIG. 5